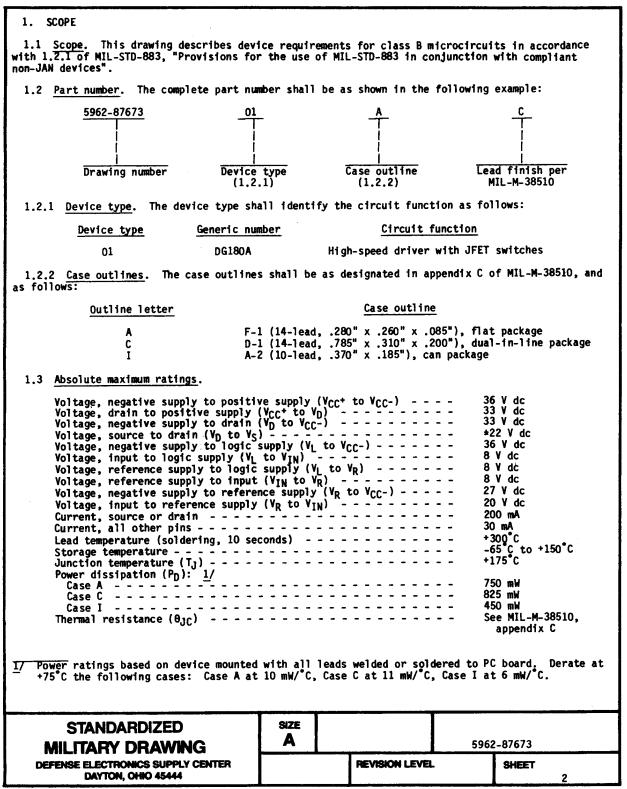
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STANDARDIZED MILITARY DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE			_	CHECKED BY Ray Monnin APPROVED BY					MICROCIRCUIT, LINEAR, ANALOG SWITCH WITH DRIVER, MONOLITHIC SILICON															
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1.4 Recommended operating conditions.

2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- $3.2\,$ Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Logic diagram. The logic diagram shall be as specified on figure 1.
 - 3.2.3 Truth table. The truth table shall be as specified on figure 1.
 - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.
 - 3.3.1 AC test circuit. AC test circuits shall be as specified on figure 2.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

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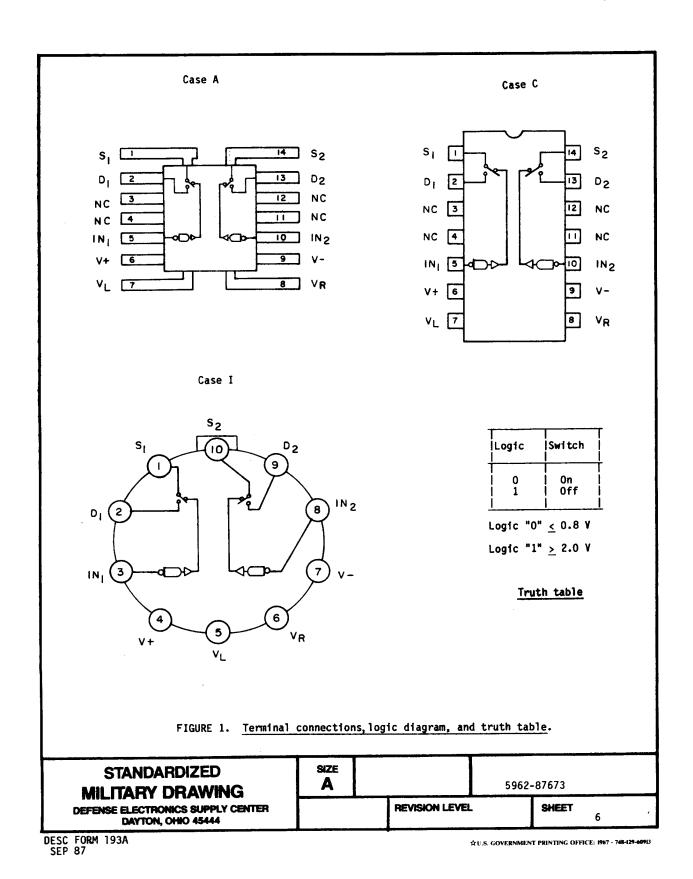
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Resistance (on) Rps drain-to-source	V+ = 15 V, V (unless ot) V _D = -7.5 V I _S = -10 mA V _{IN} = 0.8 V	$T_A < +125^{\circ}C$ $V = \frac{1}{x} -15$ V, $V_L = 5$ V herwise specified)	subgroups	Min 2	Max 10	Ω
drain-to-source	Is = -10 mA V _{IN} = 0.8 V		1, 2, 3	2	10	Ω
Source leakage Is(
current (off)	OFF) $\begin{vmatrix} V^+ = 10 & V_1 & V_2 \\ V_1 = -10 & V_2 & V_3 \end{vmatrix}$	- = -20 V V _S = 10 V,	1	-10.0	10.0	nA
	V _{IN} = 2 V		2, 3	-1000	1000	
i !	$ V_D = -7.5 \text{ V},$ $ V_{TN} = 2 \text{ V}$	$ V_D = -7.5 \text{ V}, V_S = 7.5 \text{ V}, V_{IN} = 2 \text{ V}$		-10.0	10.0	Ť
·	IN - 2			-1000	1000	
Drain leakage I _{D(1}	OFF) V _D = 7.5 V,	V _D = 7.5 V, V _S = -7.5 V, V _{IN} = 2 V		-10.0	10.0	T
Current (off)	IN			-1000	1000	T
	 V+ = 10 V, V V- = 10 V V	V+ = 10 V, V- = -20 V V _D = 10 V, V _S = -10 V, V _{IN} = 2 V		-10.0	10.0	
	V _{IN} = 2 V			-1000	1000	
Channel leakage ID(current (on) IS(ON)+ VS = VD = -7 ON) VIN = 0.8 V	.5 V,	1 1	-2.0	2.0	Ţ
-5(1	ON)			-200	200	1
Low level input IIL	V _{IN} under te	st = 0 V	1, 2, 3	-250	10.0	μА
High level input I I V I I V I I V I I		st = 5 V	1 1	-10.0	10.0	T
		2, 3	-20	20	T 	

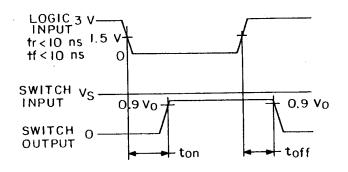
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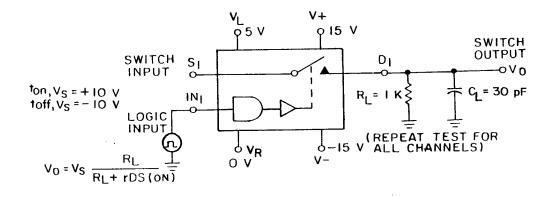
Test	Symbol	Cond -55°C < Ta	itions < +125°C	 Group A subgroups	Lim	Unit	
	İ	-55°C < TA < +125°C V+ = 15 V, V- = -15 V, V _L = 5 V (unless otherwise specified)		V	Min		Max_
Positive supply	I _{CC+}	V _{IN} = 0 V		1		1.5	. mA
current		1		2		1.5	<u>į</u>
		[3		2.5	<u> </u>
		V _{IN} = 5 V		1	<u>,,, ,, ,, ,, ,, ,, ,, ,, ,, ,, ,, ,, ,,</u>	1.5	1
				2		1.5	<u> </u>
				3		2.5	<u> </u>
Negative supply	I _{CC} -	 V _{IN} = 5 V	. 5 V		-5.0	<u> </u>	1
current	"			2	-5.0		1
				3	-8.0		<u> </u>
		$V_{IN} = 0 V$		1	-5.0	<u> </u>	<u> </u>
				2	-5.0		† †
				3	-8.0	<u> </u>	
Logic supply current		$V_{IN} = 0 V \text{ and } V_{IN} = 5 V$		1		4.5	
	-					4.5	
	!			3		7.5	1
Reference supply	IR	$V_{IN} = 0 \text{ V and } V_{IN} = 5 \text{ V}$		1	-2.0		1
current	"			2	-2.0	<u> </u>	
		[[3	-2.5	<u> </u>	<u> </u>
Functional tests		See 4.3.1c		7		<u> </u>	<u> </u>
Turn on time	ton	 See figure 2	e figure 2			300	_ ns
	"			10,11 1/		450	[
Turn off time	toff	 See figure 2		9		250	_
				10,11 1/		350	
1/ Guaranteed if	not test	ted.		<u> </u>	61		
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Logic input for off to on condition





 V_0 is the steady state output with the switch on. Feedthrough via switch capacitance may result in spikes at the leading and trailing edge of the output waveform. Switch output waveform shown for V_S = constant with logic input waveform as shown. Note that V_S may be + or - as per switching time test circuit.

FIGURE 2. AC switching diagram.

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- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification and review.</u> DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - Test conditions A or C using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, 6, and 8 of method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 7 tests shall include verification of the truth table.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - Test condition A or C using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
 Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*,2,3,7,9
Group A test requirements (method 5005)	 1,2,3,7,9,
Groups C and D end-point electrical parameters (method 5005)	1

* PDA applies to subgroup 1.

** Subgroups 10 and 11, if not tested, shall be guaranteed to the limits as specified in table I.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number 	Vendor similar part number <u>1</u> /
5962-8767301AX	17856 32293	DG180AP/883 DG180AP/883
5962-8767301CX	17856 32293	DG180AL/883 DG180AL/883
5962-8767301IX	17856 32293	DG180AA/883 DG180AA/883

Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
17856	Siliconix, Incorporated 2201 Laurelwood Road Santa Clara, CA 95054
32293	Intersil, Incorporated 10600 Ridgeview Court Cupertino, CA 95014

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